

Superresolution imaging based on high-refractive-index optical fiber bundles

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Abstract: During the past few years, we introduced different elements and instruments of THz waveguide and fiber optics based on sapphire shaped crystals [1–4]. Such crystals are fabricated using the Edge-defined Film-fed Growth technique in ISSP RAS. Recently, we developed a “THz focons”, [5] or bundle, based on the array of sapphire fibers with $n > 3$, that capture the THz near-field with the resolution which overcome the Abbe diffraction limit. The parallel fiber bundle transmit the THz image from plane to plane with mean value of 0.53λ of spatial resolution, while, at certain regions of the bundle, it is as low as 0.3λ [6]. The tapered high refractive index fiber bundle transmit the THz near field from sample to image plane with the resolution as high as $0.25\text{--}0.3\lambda$ and, then, scales it by a factor of 3 [7]. This makes possible to read out the THz near-field from the output facet of the bundle using conventional diffraction limited optics. Thus developed “THz focon” allows to overcome the Abbe diffraction limit and to perform the THz near-field imaging using common diffraction-limited lens- or mirror-based THz optics.

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